

10/18/04

Sheet 1 of 1

Based on Form PTO-1449  
(3/90)

ATTY. DOCKET NO.

455610-2590.1

SERIAL NO.

10/673,736

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Martin MILLER et al.

FILING DATE

September 29, 3003

GROUP

2117

U.S. PATENT DOCUMENTS

Examiner:Phung M. Chung

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/PCI/	AA	4,633,465	12/30/86	Fitch et al.	↓	↓	
/PCI/	AB	5,337,403	08/09/94	Klingman			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

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							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

/Phung Chung/

DATE CONSIDERED

10/11/2007

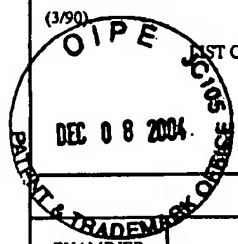
\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

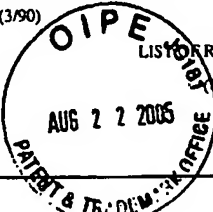
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U.S. PATENT DOCUMENTS				Examiner: Phung M. Chung			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
IPC/	AA	5,654,987	08/05/97	Nakamura			
	AB	5,726,607	03/10/98	Brede et al			
	AC	5,825,825	10/20/98	Altmann et al			
	AD	5,900,755	05/04/99	Toeppen et al			
	AE	6,215,363	04/10/01	Conta et al			
	AF	6,295,327	09/25/01	Takla			
	AG	6,445,230	09/03/02	Rupp et al			
	AH	4,680,778	07/14/87	Krinock			
	AI	5,943,378	08/24/99	Keba et al			
	AJ	6,188,737	02/13/01	Bruce et al			
	AK	5,914,592	06/22/99	Saito			
	AL	5,789,954	08/04/98	Toeppen et al			
IPC/	AM	4,694,244	08/15/87	Whiteside et al			
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
IPC/	AN	JP4105070	04/07/92	Japan			Abstract
	AO	JP5196641 ✓	08/06/93	Japan			Abstract
	AP	JP5264595 ✓	10/12/93	Japan			Abstract
	AQ	JP8220144	06/22/99	Japan			Abstract
	AR	JP9005362 ✓	01/10/97	Japan			Abstract
	AS	JP10163859 ✓	06/19/98	Japan			Abstract
	AT	JP11098876 ✓	04/09/99	Japan			Abstract
	AU	JP62003544 ✓	01/09/87	Japan			Abstract
	AV	EP 0 631 143 ✓	12/28/94	Europe			✓
IPC/	AW	EP 0 241 142 ✓	10/14/87	Europe			✓
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
IPC/	AY	✓	Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 <sup>rd</sup> Edition, McGraw-Hill, New York, 1997, pp 229-249				
	AZ	✓	Using FPGAs for Digital Applications, Actel Corporation, April 1996				
	BA	✓	HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999				
	BB	✓	Infimium DCA, Agilent Technologies, March 7, 2002				
IPC/	BC	✓	Communication waveform measurements, Hewlett Packard, June 26, 1996				
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	BD						
	BE						
	BF						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	BG						Abstract
	BH						Abstract
	BI						
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
IPC/	BJ	Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994					
IPC/	BK	R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999					
	BL	Technology Standards, Tektronix Website ( <a href="http://www.tek.com/Measurement/Solutions/tech_standards/index.htm?wt=257">www.tek.com/Measurement/Solutions/tech_standards/index.htm?wt=257</a> ) date?					
	BM	Communications Signal Analyzer, Tektronix Website ( <a href="http://www.tektronix.com/ops/24">www.tektronix.com/ops/24</a> ) date?					
	BN	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website ( <a href="http://www.tektronix.com/accessories/">www.tektronix.com/accessories/</a> ) date?					
	BO	Design of FIR Filters by Windowing, MIT Website, ( <a href="http://web.mit.edu/6.555/www/fir.html">http://web.mit.edu/6.555/www/fir.html</a> ) date?					
	BP	A New Digital PLL at the Technische Universität Berlin, Technische Universität Berlin Website ( <a href="http://www.tu-berlin.de/~gottsch/tuberlin.html">www.tu-berlin.de/~gottsch/tuberlin.html</a> ) date?					
	BQ	Low Jitter Digital PLL - ZL30407, Zentek Semiconductor Website, ( <a href="http://products.zentek.com/product_products/new_dmc.html">http://products.zentek.com/product_products/new_dmc.html</a> ) date?					
	BR	Michael K. Williams, et al., A Discussion of Methods for Measuring Low Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-650 date?					
	BS	Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000					
	BT	Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002					
	BU	"Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999					
	BV	Andy Baldman, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002					
	BW	University of New Hampshire Technical Document, "Fast Ethernet" February 12, 2003 has not been received					
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
IPC/ ↓	AA	6,112,160	08/29/00	Salant et al.	↓	↓		
	AB	4,876,655	10/24/89	Carlton et al.				
	AC	5,180,971	01/19/93	Montijo				
	AD	6,522,122	02/18/03	Watanabe et al.				
	AE	5,432,791	07/11/95	Gancarcik				
	AF	6,539,318	03/25/03	Miller et al.				
	AG	6,356,127	03/12/02	Klipper et al.				
	AH	4,758,963	07/19/88	Gordon et al.				
	AI	4,843,309	06/27/89	Kareem et al.				
	AJ	6,571,186	05/27/03	Ward				
	IPC/	AK	2003/0163266	08/28/03			Ward et al.	↓
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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IPC/ ↓	AL	EP 0 444 875	09/04/91	Europe	↓	↓	✓	
	AM	EP 1 244 241	09/25/02	Europe			✓	
	AN	EP 1 074 845	02/07/01	Europe			✓	
	AO	EP 1 118 866	07/25/01	Europe			✓	
	IPC/	AP	WO 00/60806	10/02/00			WIPO	✓
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
IPC/	AQ	✓	Dennis Dickerson, "Fiber Optic Test and Measurement (Chapter 8); Prentice Hall PTR, 1998, pps. 284-338					
↓	AR	✓	Adam Healey et al., "Fast Ethernet Consortium - 100 Base-TX PMD Test Suite", Version 2.4 and Version 2.5; InterOperability Lab, 1998-1999					
IPC/	AS	✓	Adam Healey, "Fast Ethernet Consortium Notebook", 1996-1997 14 pps.					
	AT							
	AU							
	AV							
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U.S. PATENT DOCUMENTS

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/PC/	AA	6,549,859	04/15/03	Ward			
	AB	5,714,878	02/03/98	Saito et al.			
	AC	2003/0004664	01/02/03	Ward et al.			
	AD	6,009,132	12/28/99	Sholtz			
	AE	5,978,742	11/02/99	Pirkerd			
	AF	5,761,434	06/02/98	Hewitt			
	AG	5,953,071	09/14/99	Van Zon			
	AH	6,615,148	09/02/03	Pickerd			
	AI	6,642,926	11/04/03	Letts			
	AJ	6,044,123	03/28/00	Takla			
	AK	5,999,163	12/07/99	Ivers et al.			
	AL	5,214,784	05/25/93	Ward et al.			
	AM	5,761,537	06/02/98	Sturges et al.			
	AN	6,311,138	10/30/01	Miller			
	AO	5,402,443	03/28/95	Wong			
/PC/	AP	6,643,346	11/04/03	Pedrotti et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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Sheet 1 of 1

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
/PC/	AA	6,546,345	04/08/03	Ghiasi	↓	↓		
/PC/	AB	6,278,357	08/21/01	Croushore et al.				
/PC/	AC	6,366,631	04/02/02	Nakayama et al.				
/PC/	AD	5,966,684	10/12/99	Richardson et al.				
/PC/	AE	5,631,759	05/20/97	Bogdan et al.				
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